

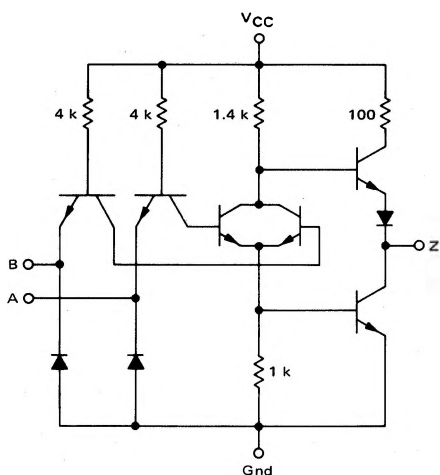
QUAD 2-INPUT "NOR" GATE

MC5400/7400 series

MC5402 • MC7402

Add Suffix F for TO-86 ceramic package (Case 607).
 Suffix L for TO-116 ceramic package (Case 632).
 Suffix P for TO-116 plastic package (Case 605) MC7402 only.

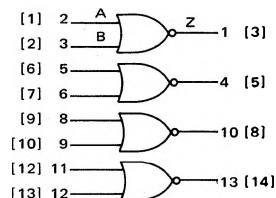
CIRCUIT SCHEMATIC 1/4 OF CIRCUIT SHOWN



V_{CC} = Pin 14 [4]
 Gnd = Pin 7 [11]

[FLAT]
 Pkg
 Pin

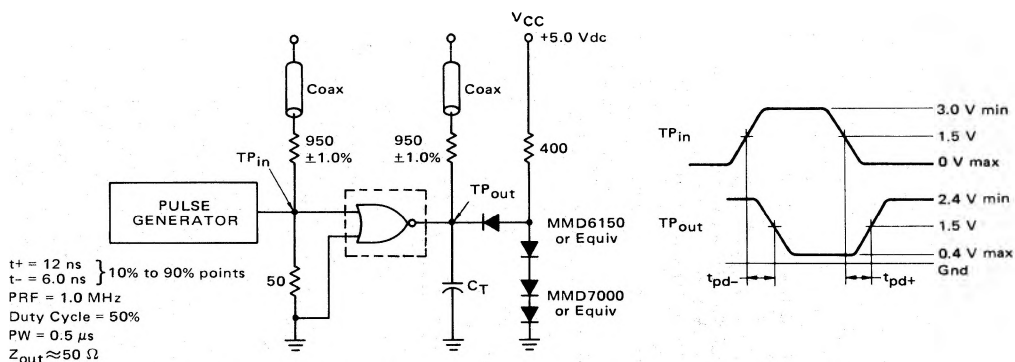
DIL
 Pkg
 Pin



Positive Logic: $Z = \overline{A + B}$
 Negative Logic: $Z = \overline{A} \cdot \overline{B}$

Input Loading Factor = 1
 Output Loading Factor = 10
 Total Power Dissipation = 40 mW typ/pkg
 Propagation Delay Time = 10 ns typ

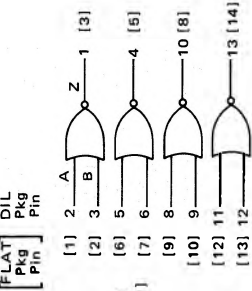
SWITCHING TIME TEST CIRCUIT AND WAVEFORMS



$C_T = 15 \text{ pF}$ = total parasitic capacitance, which includes probe, wiring, and load capacitances.

The coax delays from input to scope and output to scope must be matched. The scope must be terminated in 50-ohm impedance. The 950-ohm resistor and the scope termination impedance constitute a 20:1 attenuator probe. Coax shall be CT-070-50 or equivalent.

MC5402, MC7402 (continued)



$V = V_{CC} = \text{Pin 14 [4]}$
 $\text{Gnd} = \text{Pin 7 [11]}$

ELECTRICAL CHARACTERISTICS

Test procedures are shown for only one gate. The other gates are tested in the same manner. Further, test procedures are shown for only one input of the gate under test. To complete testing, sequence through remaining inputs.

MC5402
MC7402

Characteristic		Pin Under Test	MC5402 Test Limits -55 to +125°C						MC7402 Test Limits 0 to +70°C						TEST CURRENT /VOLTAGE APPLIED TO PINS LISTED BELOW :												for all tests in addition to the pins listed below:										
			Min		Max		Unit	Min		Max		Unit	TEST CURRENT /VOLTAGE APPLIED TO PINS LISTED BELOW :																								
			TEST CURRENT /VOLTAGE APPLIED TO PINS LISTED BELOW :																																		
Input	Forward Current	Symbol	I _F	A	-	-1.6	mAdc	-	-1.6	mAdc	-	-	I _{OL}	V _{IL}	V _{IH}	V _{IHH}	V _{R1}	V _{R2}	V _{th1}	V _{th0}	V _{CC}	V _{CCL}	V _{CCH}	Gnd	*												
																										TEST CURRENT /VOLTAGE APPLIED TO PINS LISTED BELOW :											
																										TEST CURRENT /VOLTAGE APPLIED TO PINS LISTED BELOW :											
Leakage Current		Symbol	I _{R1}	A	-	40	μAde	-	40	μAde	-	-	-	-	A	-	-	-	-	-	-	-	-	-	B*												
																										TEST CURRENT /VOLTAGE APPLIED TO PINS LISTED BELOW :											
																										TEST CURRENT /VOLTAGE APPLIED TO PINS LISTED BELOW :											
Output	Output Voltage	Symbol	V _{OL}	Z	-	0.4	Vdc	-	0.4	Vdc	-	-	Z	-	-	-	-	-	-	-	-	-	-	-	B*												
																										TEST CURRENT /VOLTAGE APPLIED TO PINS LISTED BELOW :											
																										TEST CURRENT /VOLTAGE APPLIED TO PINS LISTED BELOW :											
Short-Circuit Current		Symbol	I _{SC} [†]	Z	-20	-55	mAde	-18	-55	mAde	-	-	-	-	-	-	-	-	-	-	-	-	-	-	Z,A,B*												
																										TEST CURRENT /VOLTAGE APPLIED TO PINS LISTED BELOW :											
																										TEST CURRENT /VOLTAGE APPLIED TO PINS LISTED BELOW :											
Power Requirements (Total Device) Power Supply Drain		Symbol	I _{PDH}	V	-	27	mAde	-	27	mAde	-	-	-	-	-	-	-	-	All Inputs	-	-	-	-	-	-												
																										TEST CURRENT /VOLTAGE APPLIED TO PINS LISTED BELOW :											
																										TEST CURRENT /VOLTAGE APPLIED TO PINS LISTED BELOW :											
Switching Parameters	Turn-On Delay	Symbol	I _{PDL}	V	-	16	mAde	-	16	mAde	-	-	Pulse In	Pulse Out	-	-	-	-	-	-	-	-	-	-	A*,B*												
																										TEST CURRENT /VOLTAGE APPLIED TO PINS LISTED BELOW :											
																										TEST CURRENT /VOLTAGE APPLIED TO PINS LISTED BELOW :											
Turn-Off Delay		Symbol	t _{pd+}	A,Z	-	22**	ns	-	22**	ns	-	-	A	Z	-	-	-	-	-	-	-	-	-	-	A*												
																										TEST CURRENT /VOLTAGE APPLIED TO PINS LISTED BELOW :											
																										TEST CURRENT /VOLTAGE APPLIED TO PINS LISTED BELOW :											

*Ground inputs to gates not under test.
**Tested only at 25°C.
†Only one output should be shorted at a time.